Synthesis of Thin Films

Protective coatings - Hard films

Optical coatings - Filters, mirrors, lenses

Microelectronic devices

Optoelectronic devices, Photonic devices

Electrode surfaces Photoelectric devices, photovoltaics, solar cells

Xerography, Photography, Lithography

Catalyst surfaces, Heterogeneous catalysis

Information storage, magnetic, magneto-optical, optical memories

Synthesis of Thin Films

•Crystalline, Amorphous, Microcrystalline

Monolayer, multilayer, superlattice, junctions

•Free-standing, supported

•Epitaxial (commensurate), incommensurate

Free-Standing Films

 $Fe(CO)_5 + O_2 \rightarrow amorph. Fe_2O_3$ Prepared as a film on a NaCl crystal support

Dissolution of NaCl in water = Free-standing film

Synthesis of Thin Films

FILM PROPERTIES DEPEND ON NUMEROUS CONSIDERATIONS:

Thickness

Surface : volume ratio

Structure, surface versus bulk, surface reconstruction, surface roughness

Hydrophobicity, hydrophilicy (Si-OH vs. Si-H)

Composition

Texture: single crystal, microcrystalline, domains, orientation: Si (100) vs. (111)

Form: supported or unsupported, nature of substrate

Surfaces

Surface energy [J m⁻²] a scalar **Surface stress** [J m⁻²] a tensor

Same for liquids, different for solids

Surface tension [J m⁻²] the work done in creating unit area of new surface (= Surface energy in one-component systems)

Surface Energy

Surface energy [J m⁻²] depends on:

•The distance of the face from the center of the crystal

•Miller indices

•Surface roughness

•The radius of curvature



Cubic (rocksalt) MgO crystal: different netplanes

Surfaces The TSK (TLK) Model of a Surface (Kossel/Stranski)

Terrace Step/Ledge Kink Vacancy Adatom Island





The acetone molecule (in colored spheres) attached to (A) the edge of bilayer graphene (carbon atoms are represented as black balls), (B) the edge of four layer graphene, (C) on a step formed from bilayer graphene, and (D) on a step formed from trilayer graphene.

Surfaces





Screw dislocation on graphite Spiral growth

Thin-film growth mechanisms

The growth of epitaxial (homogenous or heterogeneous) thin films on a single crystal surface depends on the interaction strength between adatoms and the surface.

• Volmer–Weber (VW) growth - adatom-adatom interactions are stronger than those of the adatom with the surface, the formation of three-dimensional adatom clusters or islands, coarsening, rough multi-layer films

• Frank–van der Merwe (FM) growth - adatoms attach preferentially to surface sites, atomically smooth layers, layer-by-layer growth

• **Stranski–Krastanov growth** - an intermediary process, both 2D layer and 3D island growth, transition from the layer-by-layer (wetting layer) to island-based growth occurs at a critical layer thickness, dependent on the chemical and physical properties, such as surface energies and lattice parameters, of the substrate and film

Thin-film growth mechanisms



Symmetry at Surfaces



AFM of C atoms within the hexagonal graphite unit cells. Image size 2×2 nm².





Surface Diffusion

Surface diffusion coefficient D

 $D = a^2 k_s$ a ... effective hopping distance between sites

k_s... site-to-site hopping rate of an adatom

 $k_s = A \exp(-V_s/k_bT)$ $V_s \dots$ potential-energy barrier to hopping from site to site

T ... substrate temperature

Higher temperature = **Faster diffusion**





The dissociative collision of a CH₄ molecule with a nickel surface does not significantly perturb the nickel atom at the impact point.



Si(111) Surface



Silicon "diamond lattice" structure

a = 5.463 Å

Si(111) = a set of atomic planes

One plane outlined with red

Si (111) etches more slowly than (001) Si (111) oxidizes twice as rapidly as (001)

Si(111) Surface

A top view of the atomic arrangement for the (111) plane





orange = the top layer green = deeper layers

Si(111) Surface

a) Unoccupied states

b) Occupied states





20 Å



Figure 7. STM topographs of the clean Si(111)-(7×7) surface: (a) unoccupied states imaged at +2.0 V crystal bias, (b) occupied states imaged at -2.0 V crystal bias. The 12 adatoms are clearly visible in both images, and in the occupied state image the stacking fault and differences between corner and center adatoms are also seen. Courtesy of V. Ukraintsev, J. C. Camp, and J. T. Yates, Jr.

Reconstruction

Relaxation = energy lowering, no change in symmetry

Reconstruction = the surface atoms rearrange to a more energetically stable configuration.

Symmetry lowering 2D symmetry – 17 plane groups / 230 bulk space groups

7x7 Reconstruction

When (111) surface of Si is heated to high temperatures under the Ultra-High Vacuum conditions the surface atoms rearrange to a more energetically stable configuration called 7x7 reconstruction.

Thin Films





STM image of Si(111) surface

7x7 Reconstruction





7x7 Reconstruction

3D representation of the 7x7 STM image The image area is 18x8 nm², the height of the "bumps" is only about 0.04 nm



Si(100) Surface





a)

STM images of the silicon-silicon dimers imaged with

(a) $V_{\text{sample}} = -2.0 \text{ V}$ (b) $V_{\text{sample}} = 2.3 \text{ V}$

The filled and empty states of these highly ordered dimers can be probed by biasing the surface in the opposite directions

The dimensions of the figure are 2.3 nm x 7.7nm.



H-terminated Si(100) Surface





Synthesis of Thin Films

MAIN METHODS OF SYNTHESIZING THIN FILMS:

CHEMICAL, ELECTROCHEMICAL, PHYSICAL

Cathodic deposition, Anodic deposition, Electroless deposition Thermal oxidation, nitridation Chemical vapor deposition (CVD) Metal organic chemical vapor deposition (MOCVD) Molecular beam epitaxy, supersonic cluster beams, aerosol deposition Liquid phase epitaxy Self-assembly, surface anchoring, SAM Discharge techniques, RF, microwave Laser ablation Cathode sputtering, vacuum evaporation

Synthesis of Thin Films ***** CATHODIC DEPOSITION

Two electrodes, dipped into electrolyte solution External potential applied Metal deposition onto the cathode as thin film Anode metal slowly dissolves

† ELECTROLESS DEPOSITION

Spontaneous, No applied potential Depends on electrochemical potential difference between electrode and solution redox active species to be deposited

Both methods limited to metallic films on conducting substrates

***** ANODIC DEPOSITION

Deposition of oxide films, such as alumina, titania Deposition of conducting polymer films by oxidative polymerization of monomer, such as thiophene, pyrolle, aniline Oxide films formed from metallic electrode in aqueous salts or acids Thin Films

Porous Alumina Films

Example:

Anodic oxidation of aluminum in oxalic or phosphoric acid

Pt|H₃PO₄, H₂O|Al

 $AI \rightarrow AI^{3+} + 3e^{-}$ anode

 $PO_4^{3-}+2e^- \rightarrow PO_3^{3-}+O^{2-}$ cathode

 $2Al^{3+} + 3O^{2-} \rightarrow \gamma - Al_2O_3$ (annealing) $\rightarrow \alpha - Al_2O_3$

overall electrochemistry: $2AI + 3PO_4^{3-} \rightarrow Al_2O_3 + PO_3^{3-}$

The applied potential controls the oxide thickness and the rate at which it forms, oxide anions from solution have to diffuse through an Al_2O_3 layer of growing thickness on the reacting Al substrate, to attain an equilibrium thickness of the alumina film

Porous Alumina Films

Self-organizing process observed, whereby a regular array of size tunable hcp pores form and permeate orthogonally through the alumina film



Exceptionally useful process for creating controlled porosity membranes, photonic gap materials, template for synthesizing semiconductor nanostructures, host for synthesizing and organizing aligned carbon nanotubes for high intensity electron emission displays, and last but not least, fuel cell electrode materials

AFM Image of Porous Alumina Film



31

AFM Image of Porous Alumina Film



Porous Alumina Films



SYNTHESIS OF THIN FILMS

***** THERMAL OXIDATION

Oxides, metal exposed to a glow discharge

 $Al + O_2 \rightarrow (RT) Al_2O_3$, thickness 3-4 nm

Similar method applicable to other metals, Ti, V, W, Zr etc

Nitrides, exceptionally hard, high temperature protective coating

 $Ti + NH_3 \rightarrow TiN$

 $Al + NH_3 \rightarrow AlN$

Synthesis of Thin Films

CHEMICAL VAPOR DEPOSITION

Pyrolysis, photolysis, chemical reaction, discharges, RF, microwave Epitaxial films, correct matching to substrate lattice

EXAMPLES OF CVD

 $CH_4 + H_2$ (RF, MW) \rightarrow C, diamond films

 Et_4Si (thermal, air) $\rightarrow SiO_2$

 $SiCl_4$ or SiH_4 (thermal, H_2) \rightarrow a-HSi

 $SiH_4 + PH_3 (RF) \rightarrow n-Si$

 $Si_2H_6 + B_2H_6 (RF) \rightarrow p-Si$


$SiH_3SiH_2SiH_2PH_2$ (RF) \rightarrow n-Si

Me₃Ga (laser photolysis, heating) \rightarrow Ga

 $Me_3Ga + AsH_3 + H_2 \rightarrow GaAs + CH_4$

Si (laser evaporation, supersonic jet) Si_n^+ (size selected cluster deposition) \rightarrow Si

★ METAL ORGANIC CHEMICAL VAPOR DEPOSITION, MOCVD

Invented by Mansevit in 1968 Recognized high volatility of metal organic compounds as sources for semiconductor thin film preparations

MOCVD PRECURSORS, SINGLE SOURCE MATERIALS

Me₃Ga, Me₃Al, Et₃In NH₃, PH₃, AsH₃ H₂S, H₂Se Me₂Te, Me₂Hg, Me₂Zn, Me₄Pb, Et₂Cd All toxic materials – a problem of safe disposal of toxic waste

Example - IR detectors: $Me_2Cd + Me_2Hg + Me_2Te (H_2, 500^{\circ}C) \rightarrow Cd_xHg_{1-x}Te$

Specially designed MOCVD reactors Controlled flow of precursors to single crystal heated substrate Most reactions occur in range 400-1300°C Complications of diffusion at interfaces, disruption of atomically flat epitaxial surfaces/interfaces occurs during deposition Photolytic processes (photoepitaxy) help to bring the deposition temperatures to more reasonable temperatures

REQUIREMENTS OF MOCVD PRECURSORS

RT stable, no polymerization, decomposition Easy handling, simple storage Not too reactive Vaporization without decomposition at modest T < 100°C Low rate of homogeneous pyrolysis (gas phase) wrt heterogeneous decomposition (surface)

HOMO: HETERO rates ~ 1:1000

Heterogeneous reaction on substrate Greater than on other hot surfaces in reactor Not on supports, vessel etc Ready chemisorption of precursor on substrate Detailed surface and gas phase studies of structure of adsorbed species, reactive intermediates, kineticss, vital for quantifying film nucleation and growth processes Electronic and optical films synthesized in this way Semiconductors, metals, silicides, nitrides, oxides, mixed oxides (e.g., high T_c superconductors)

CRITICAL PARAMETERS IN MATERIALS PREPARATION FOR SYNTHESIS OF THIN FILMS

Composition control Variety of materials to be deposited Good film uniformity over large areas to be covered, $> 100 \text{ cm}^2$ **Precise reproducibility** Growth rate, thickness control, 2-2000 nm layer thickness **Precise control of film thickness = accurate control of deposition,** film growth rate Crystal quality, epitaxy High degree of film perfection **Defects degrade device performance** Purity of precursors: usually less than 10⁻⁹ impurity levels Stringent demands on starting material purity Challenge for chemistry, purifying and analyzing at the ppb level Demands exceptionally clean growth system otherwise defeats the object of controlled doping of films for device applications **Interface widths** Abrupt changes of composition and dopant concentration required, quantum confined structures **30-40 sequential layers often needed** Alternating composition and graded composition films 0.5-50 nm thickness required with atomic level precision All of the above has been more-or-less perfected in the electronics and optics industries Thin Films

TECHNIQUES USED TO GROW SEMICONDUCTOR FILMS AND MULTILAYERED FILMS

MOCVD

Liquid phase epitaxy

Chemical vapor transport

Molecular beam epitaxy

Laser ablation

PHYSICAL METHODS FOR PREPARING THIN FILMS

CATHODE SPUTTERING
Bell jar equipment
10⁻¹ to 10⁻² torr of Ar, Kr, Xe
Glow discharge created
Positively charged rare gas ions
Accelerated in a high voltage to cathode target
High energy ions collide with cathode
Sputter material from cathode
Deposits on substrate opposite cathode to form thin film
Multi-target sputtering creates composite or multilayer films

***** THERMAL VACUUM EVAPORATION

High vacuum bell jar > 10⁻⁶ torr Heating e-beam, resistive, laser Gaseous material deposited on substrate Thin films nucleate and grow Containers must be chemically inert: W, Ta, Nb, Pt, BN, Al₂O₃, ZrO₂, Graphite Substrates include insulators, metals, glass, alkali halides, silicon Sources include metals, alloys, semiconductors, insulators, inorganic salts

Epitaxy

Epitaxial reactions = surface structure controlled reactions Crystallographic orientation of the film is controlled by the substrate

Kinetic control – TD metastable phases

YMnO₃ •hexagognal in bulk •cubic perovskite film on NdGaO₃ substrates

Homoepitaxy – same compound/orientation in substrate and film Heteroepitaxy – different compounds in the substrate and film

*** MOLECULAR BEAM EPITAXY**

Million dollar thin film machine, ideal for preparing high quality artificial semiconductor quantum superlattices, ferroelectrics, superconductors Ultrahigh vacuum system $>10^{-12}$ torr Elemental or compound sources in shutter controlled Knudsen effusion cells Ar⁺ ion gun for cleaning substrate surface or depth profiling sample using Auger analyzer High energy electron diffraction for surface structure analysis Mass spectrometer for control and detection of vapor species e-gun for heating the substrate

MBE



✦ PHOTOEPITAXY

Making atomically perfect thin films under milder and more controlled conditions, Mullin and Tunnicliffe 1984

Et₂Te + Hg (pool) + H₂ (hv , 200 °C) \rightarrow HgTe + 2C₂H₆

MOCVD preparation requires 500 °C using Me₂Te + Me₂Hg

Advantages of photoepitaxy

Lower temperature operation Multilayer formation Less damage of layers Lower interlayer diffusion Easy to fabricate abrupt boundaries Less defects, strain, irregularities at interfaces

CdTe can be deposited onto GaAs at 200-250 °C even with a 14% lattice mismatch GaAs is susceptible to damage under MOCVD conditions 650-750 °C

Thin Films

EXTENSIONS OF PHOTOLYTIC METHODS - LASER WRITING AND LASER ETCHING

Caser writing: Substrate GaAs Me₃Al or Me₂Zn adsorbed layer or gas phase Focussed UV laser on film Photodissociation of organometallic precursor:

 $Me_3Al \rightarrow Al + C_2H_6$

Creates sub-micron lines of Al or Zn

Laser photoetching:
GaAs substrate
Gaseous or adsorbed layer of CH₃Br
Focussed UV laser
Creates reactive Br atoms

 $CH_3Br(g) (hv) \rightarrow CH_3(g) + Br(g)$

 $Br(g) + GaAs(s) \rightarrow GaAs...Br_n(ad)$

 $GaAs...Br_n(ad) \rightarrow GaBr_n(g) + AsBr_n(g)$

Adsorbed reactive surface Br atoms erode surface regions irradiated with laser

Vaporization of volatile gallium and arsenic bromides from surface creates sub-micron etched line

Pulsed Laser Ablation



Pulsed Laser Ablation



(a) Initial absorption of laser radiation (indicated by long arrows), melting and vaporization begin (shaded area indicates melted material, short arrows indicate motion of solid–liquid interface)

(b) Melt front propagates into the solid, vaporization continues and laser-plume interactions start to become important

(c) Absorption of incident laser radiation by the plume, and plasma formation

(d) Melt front recedes leading to eventual re-solidification.

Thin Films



SEM of a porous silicon, the pores extending from the surface of the Si(100) wafer down into the bulk, etched from n-type Si(100) (P-doped, 0.75-0.95 Ø,cm) at 77.2 mA cm⁻² for 1 min with a 1:1 solution of 49% HF(aq)/ EtOH. Scale bar is 10 μ m.

Porous Si



HF:EtOH = 1:2.5 $j = 10 \text{ mA/cm}^2$ t = 30 min53

Thin Films

Chemistry on Si Surface



Porous Si







Table 1.	Typical Bond	Energies	for	Various	Groups
	to Group(IV)				-

self	Н	С	0	F	Cl	\mathbf{Br}	Ι
292-360	416						
5 C	323	369	368	582	391	310	234
105–126 (disilene)		~			a=a	a - a	
	290	255		465	356	276	213
	292–360 210–250 (bulk) 310–340 (disilane) 105–126 (disilene) 190–210 (bulk)	292-360 416 210-250 (bulk) 323 310-340 (disilane) 105-126 (disilene) 190-210 (bulk) 290	292-360 416 210-250 (bulk) 323 369 310-340 (disilane) 105-126 (disilene)	292-360 416 336 210-250 (bulk) 323 369 368 310-340 (disilane) 105-126 (disilene) 190-210 (bulk) 290 255	292-360 416 336 485 210-250 (bulk) 323 369 368 582 310-340 (disilane) 105-126 (disilene) 190-210 (bulk) 290 255 465	292-360 416 336 485 327 210-250 (bulk) 323 369 368 582 391 310-340 (disilane) 105-126 (disilene) 190-210 (bulk) 290 255 465 356	292-360 416 336 485 327 285 210-250 (bulk) 323 369 368 582 391 310 310-340 (disilane) 105-126 (disilene) 190-210 (bulk) 290 255 465 356 276

Chemistry on Si Surface



Hydrosilylation



Chemistry on Si Surface



Carbaanion LiR, RMgX



a) Cathodic Electrografting (CEG)



Thin Films

2+2 Cycloaddition





2+2 Cycloaddition









Thin Films





G. Polymerization



SELF-ASSEMBLED MONOLAYERS

Self-assembly: spontaneous organization of molecules into stable, structurally well-defined aggregates

Self-assembled monolayers (SAM): two-dimensional ordered assemblies of long hydrocarbon chains anchored through chemical bonds to surfaces of solid inorganic substrates

Alkanethiolates on gold and alkylsiloxanes on silicon dioxide belong the most notoriously studied SAM systems

SELF-ASSEMBLED MONOLAYERS

Metal surfaces Au, Ag, Cu, Pt, Hg, Fe,... react with

Thiols	$M + RSH \longrightarrow$	M-S-R + $1/2$ H ₂
Disulfides	2 M + RSSR —	→ 2 M-S-R
Sulfides	$M + RSR \longrightarrow$	M-S-R

Same products formed in all three reactions: thiolates. RSH are more soluble and react 10³ faster with Au than RSSR.

Substrates: gold polycrystalline films on Si(SiO₂), glass, mica.

Thickness 5-300 nm, sputtering, evaporation

Atomically flat



Thin Films



71




★ Thermodynamics
Au does not form surface oxide layer
Reaction driving force:
> Au-S bond energy 160-185 kJ mol⁻¹
> van der Waals attraction between alkyl chains
6-8 kJ mol⁻¹ per CH₂
In ^tBuSH and n-C₁₈SH competition reaction, the linear alkyl thiol binds 300 – 700 times better.

Surface coverage 10^{14} molecules per cm² C₁₆ chain length ~2.2 nm, 32-40° tilted, all-trans

Chemical stability: Cu/C₁₈SH sustains HNO₃ Thermal stability: Au/RSH loses sulfur at 170-230 °C

Binding modes on Au(111)

♦ On-top sites

 \Rightarrow Hollow sites – threefold, more stable by 25 kJ mol⁻¹

♦Bridging sites – the most stable!! (QM calculations)



Au – S – C = 180°, sp Au – S – C = 104°, sp³, more stable by 1.7 kJ mol⁻¹ barrier to interconversion 10.5 kJ mol⁻¹

Thin Films

Au(111)

Hexagonal array of S, S....S distance 4.97 Å, interchain distance in crystalline paraffins 4.65 Å, tilt angles 25 - 30° to reestablish alkyl chain contacts, hollow site binding, 21.4 Å² per molecule

Ag(111) Hexagonal array of S, S....S distance 4.41 Å, on-top site binding, more tightly packed alkyl chains, no tilt

★ Kinetics Au(111) + RSH reactions proceed in two steps:

1. First step, fast (minutes), diffusion controlled Langmuir adsorption, concentration dependent (1 mM ~ 1 min, 1 μ M ~ 100 min)

2. Second step, slow (hours), disordered film orders to a 2D crystal, surface crystallization, defect healing, trapped solvent expulsion. Mechanisms: alkyl chain flipping, RS⁻ lateral diffusion, equilibrium with dissolved RSH, Au atom diffusion, Au in solution. Better crystallinity of films in polar solvents: MeOH, EtOH,...

Surface chemical derivatization

 $HS - (CH_2)_n - X$ X = CH₃, CF₃, OH, NH₂, SH, COOH, COOR, CN, CH=CH₂, C=CH, Cl, Br, OCH₃, SO₃H₂ SiMe₃, ferrocenyl,

Microfabrication

▲ Self-assembly, at thermodynamic minima, rejects defects, high degree of perfection.

A Dimension in the range 1 nm to 1000 μm, too large for chemical synthesis, too small for microlithography.

▲ High efficiency, spontaneous.

SiO₂ Surfaces

native oxide on Si silicagel

Chemical derivatization methods are based on the reactivity of the surface hydroxyl groups with various reagents



[O₃Si]—OH stands for the siliceous surface

1. Grafting

Reactions with trifunctional reagents, such as alkyltrichlorosilanes and trialkoxyalkylsilanes, lead to the three-fold attachment of the SiR groups.

 $3 [O_3Si] \longrightarrow OH + Cl_3SiR \longrightarrow \{[O_3Si] \longrightarrow O\}_3SiR + 3 HCl$ $3 [O_3Si] \longrightarrow OH + (MeO)_3SiR \longrightarrow \{[O_3Si] \longrightarrow O\}_3SiR + 3 MeOH$

2. Chlorination/Displacement Method The first step is the replacement of the Si-OH groups by more reactive Si-Cl bonds by chlorination.

$$[O_{3}Si] \longrightarrow OH + SOCl_{2} \longrightarrow [O_{3}Si] \longrightarrow Cl + HCl + SO_{2}$$
$$[O_{3}Si] \longrightarrow OH + CCl_{4} \xrightarrow{400 \circ C} [O_{3}Si] \longrightarrow Cl + COCl_{2} + HCl$$

In the subsequent step, the surface is treated with a Grignard or organolithium reagent with the formation of strong Si-C bonds.

 $[O_3Si]$ —Cl + RMgCl \longrightarrow $[O_3Si]$ —R + MgCl₂

 $[O_3Si]$ —Cl + RLi — O_3Si]—R + LiCl

3. Post Modification Method

The organic groups (R) covalently anchored to the siliceous surface by the two previous methods can be subsequently chemically modified. The most extensively developed is chemistry of 3aminopropyl(trimethoxy)silane. A large number of chemical transformations of the amino moiety to other functional groups are known.

4. Hybrid sol-gel method (co-condensation) A thin layer of a hybrid (organically modified) silica gel can be deposited on the silica surface from a solution of TEOS and (MeO)₃SiR by controlled hydrolysis and condensation.

 $(MeO)_3SiR + (MeO)_4Si + 7 H_2O \longrightarrow [O_3Si] - R + 7 MeOH$

5. Organometallic modification method

Organometallic reagents, such as metal alkyls, halides, amides, and alkoxides can be used to deposit a monolayer of metal complexes on the surface (ML_n stands for an organometallic group, M for a metal, L for a ligand, R" for a short alkyl chain, X for halogen).

 $[O_{3}Si] \longrightarrow OH + R"-ML_{n} \longrightarrow R"H + [O_{3}Si] \longrightarrow O-ML_{n}$ $[O_{3}Si] \longrightarrow OH + X-ML_{n} \longrightarrow HX + [O_{3}Si] \longrightarrow O-ML_{n}$ $[O_{3}Si] \longrightarrow OH + Me_{2}N-ML_{n} \longrightarrow Me_{2}NH + [O_{3}Si] \longrightarrow O-ML_{n}$ $[O_{3}Si] \longrightarrow OH + R"O-ML_{n} \longrightarrow R"OH + [O_{3}Si] \longrightarrow O-ML_{n}$

These organometallic moieties can serve as attachment points for further modification with long chain alcohols, thiols, carboxylic acids, phosphates, and diketonates.

 $[O_{3}Si] \longrightarrow O-ML_{n} + HOR \longrightarrow [O_{3}Si] \longrightarrow O-ML_{n-1} - OR + HL$ $[O_{3}Si] \longrightarrow O-ML_{n} + HOOCR \longrightarrow [O_{3}Si] \longrightarrow O-ML_{n-1} - OOCR + HL$









0



in Films





Evaporation Induced Self-Assembly (EISA)



Critical parameters of EISA process:

- •Molar ratio Surfactant / Inorganic precursor
 •H₂O amount
 •Volatile solvent content (Ethanol/THF)
 •Temperature
- •Relative Humidity

